

Optimization of bias rail implementations for segmented silicon sensors

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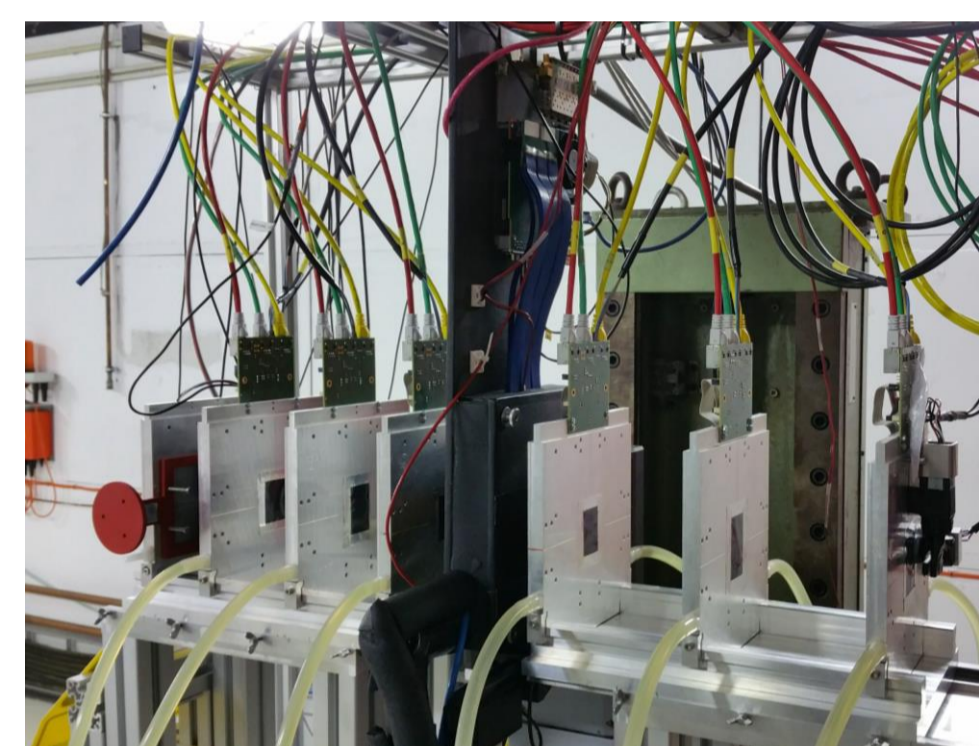
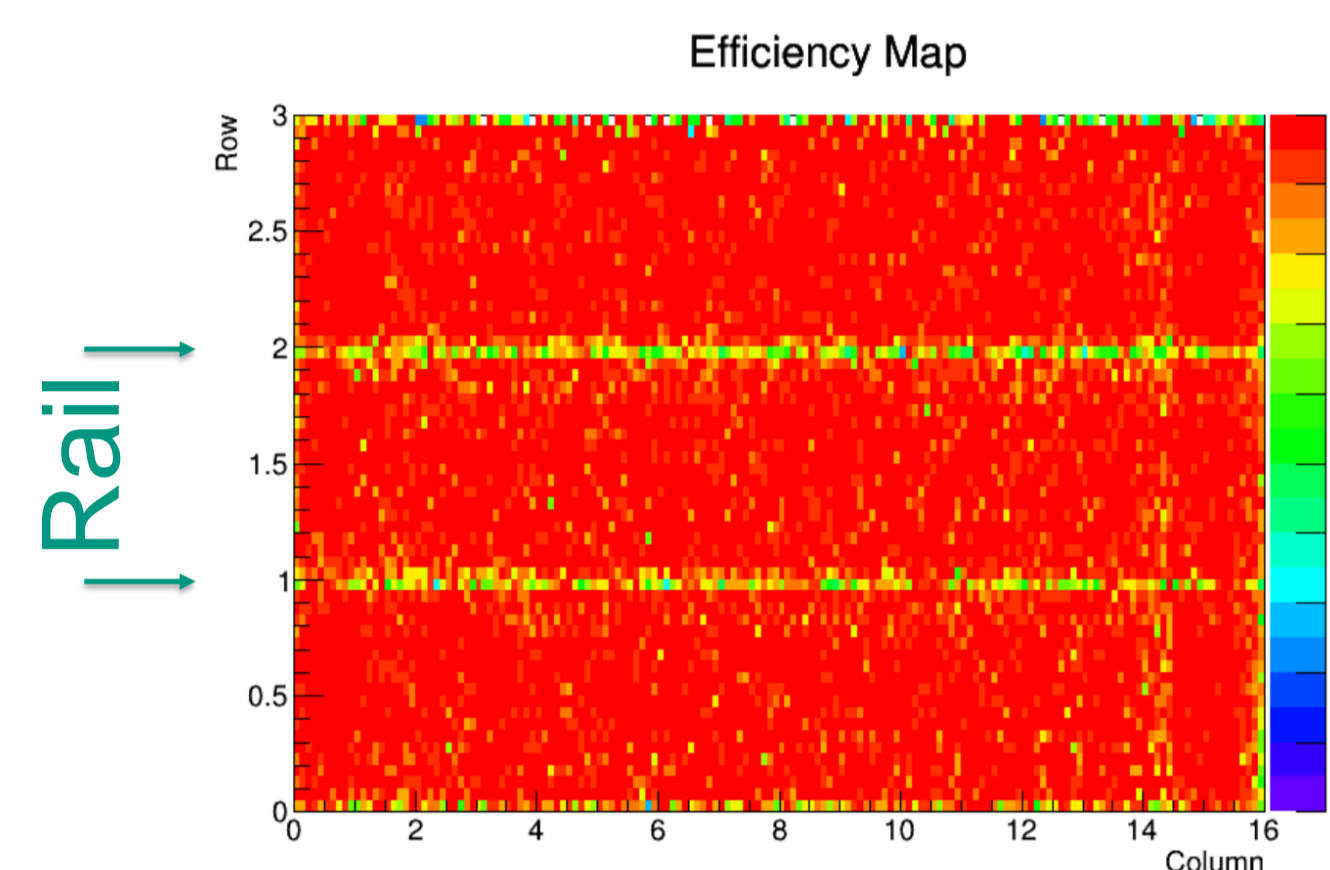


Motivation

- Aluminum bias rails necessary to test segmented silicon sensors
- Testing segmented AC coupled sensors simplified by introducing additional bias rails
- However, depending on the geometry, rails also lead to a certain amount of inefficiency

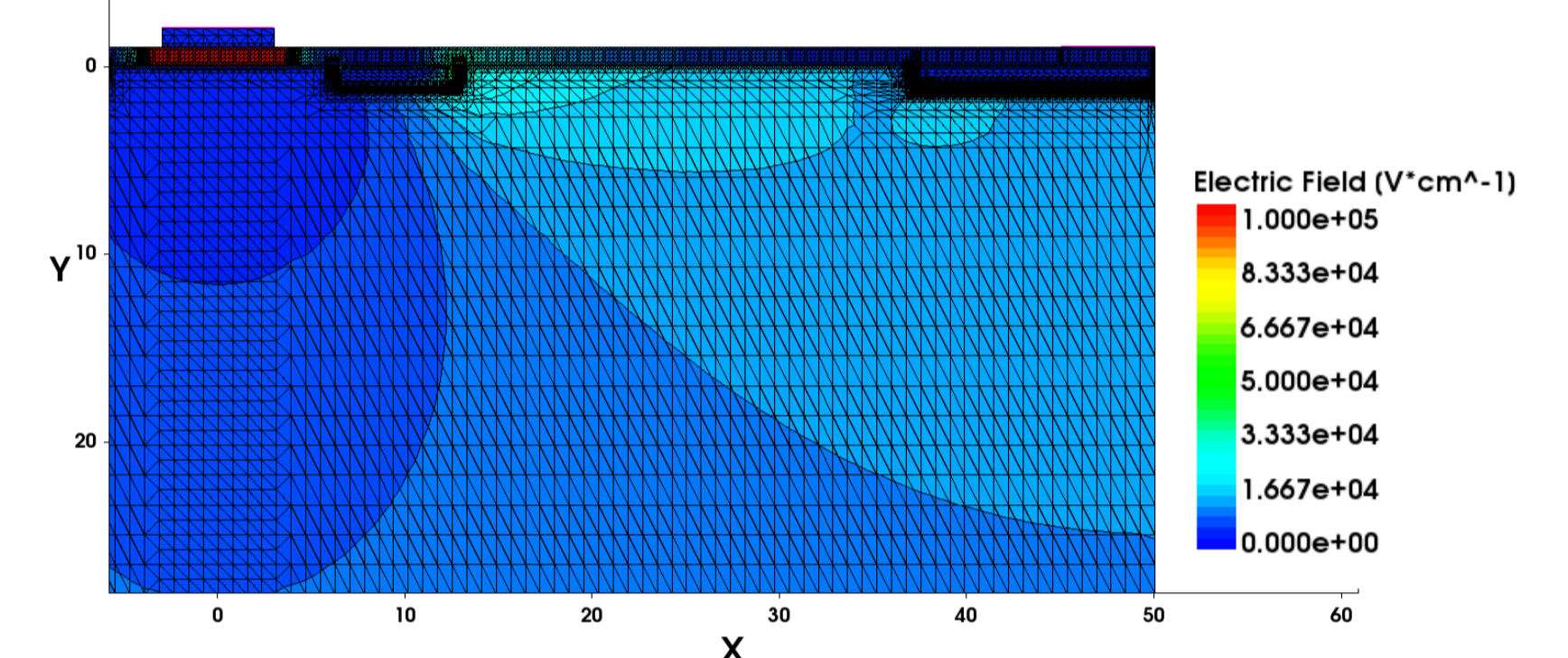
Efficiency measurement at test beam

- Macropixel sensor ($100 \times 1446 \mu\text{m}^2$) with aluminum bias rail bump bonded to binary readout chip
- 5.6 GeV positron beam at DESY, Germany
- EUDET-type beam telescope for track reconstruction



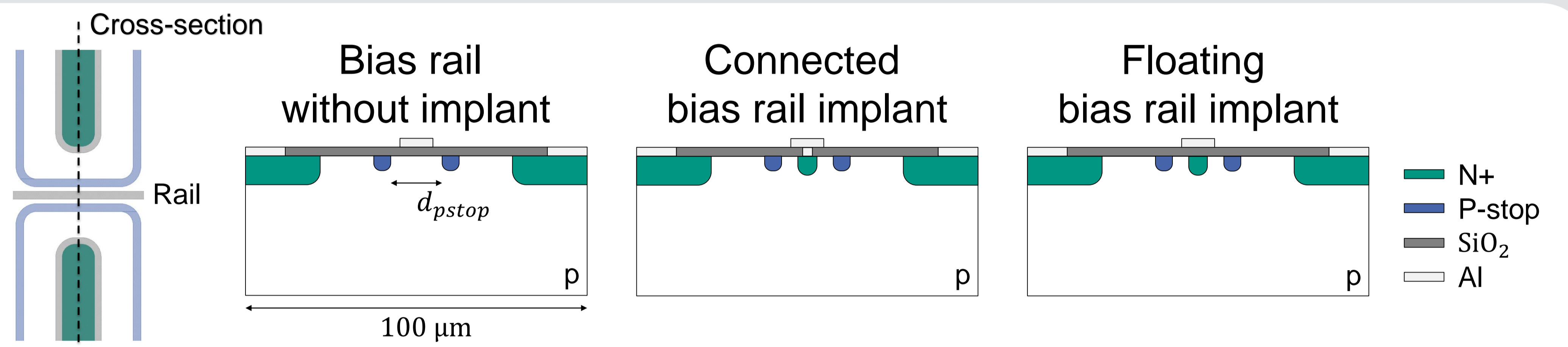
Device simulation

- TCAD simulations offer deeper understanding of possible reasons for efficiency loss
- Electric field distribution and charge collection efficiency used to determine and optimize critical parts of the sensor
- Tool: Sentaurus TCAD (Synopsys)



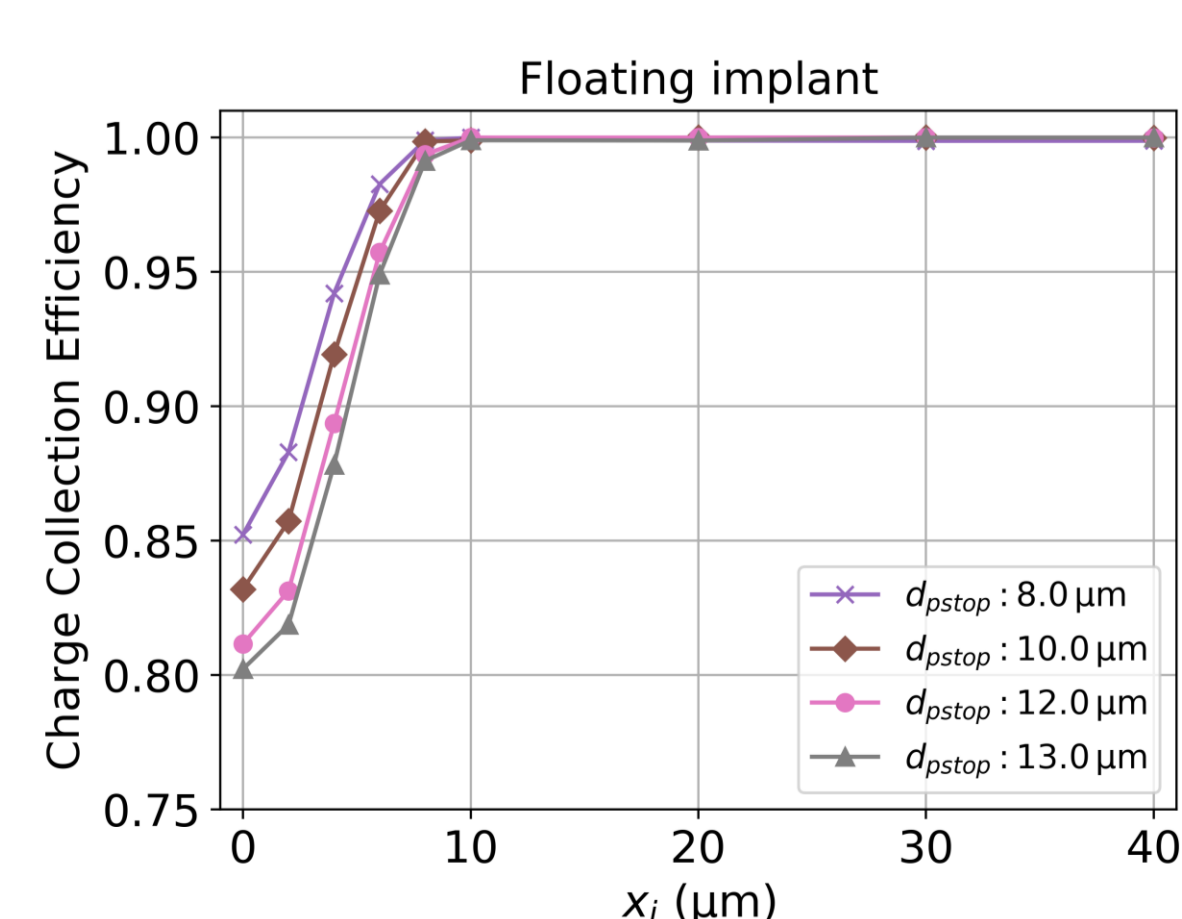
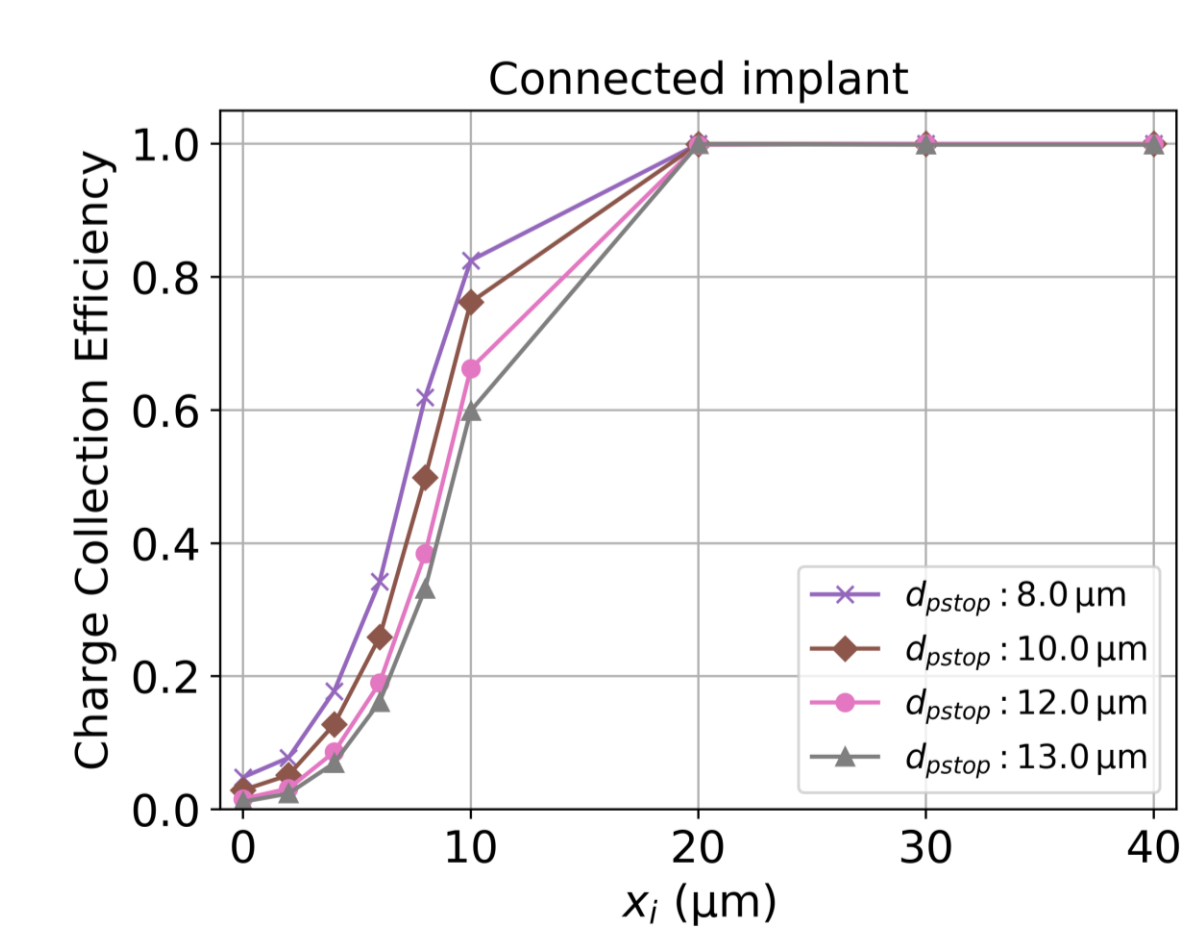
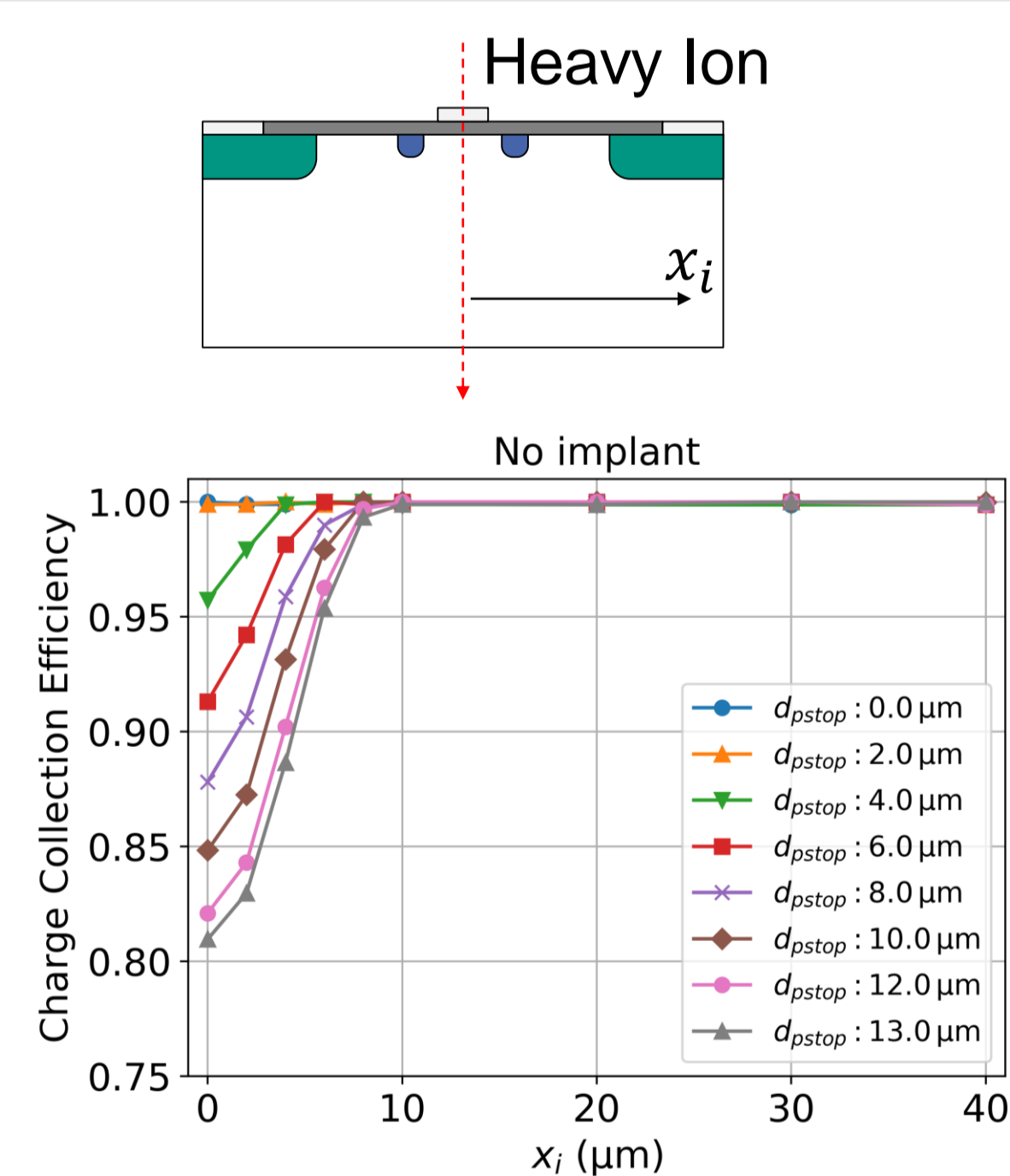
Layout

- Design study based on macropixel layout with $75 \mu\text{m}$ spacing between opposing pixels
- Investigation of three bias rail implementations



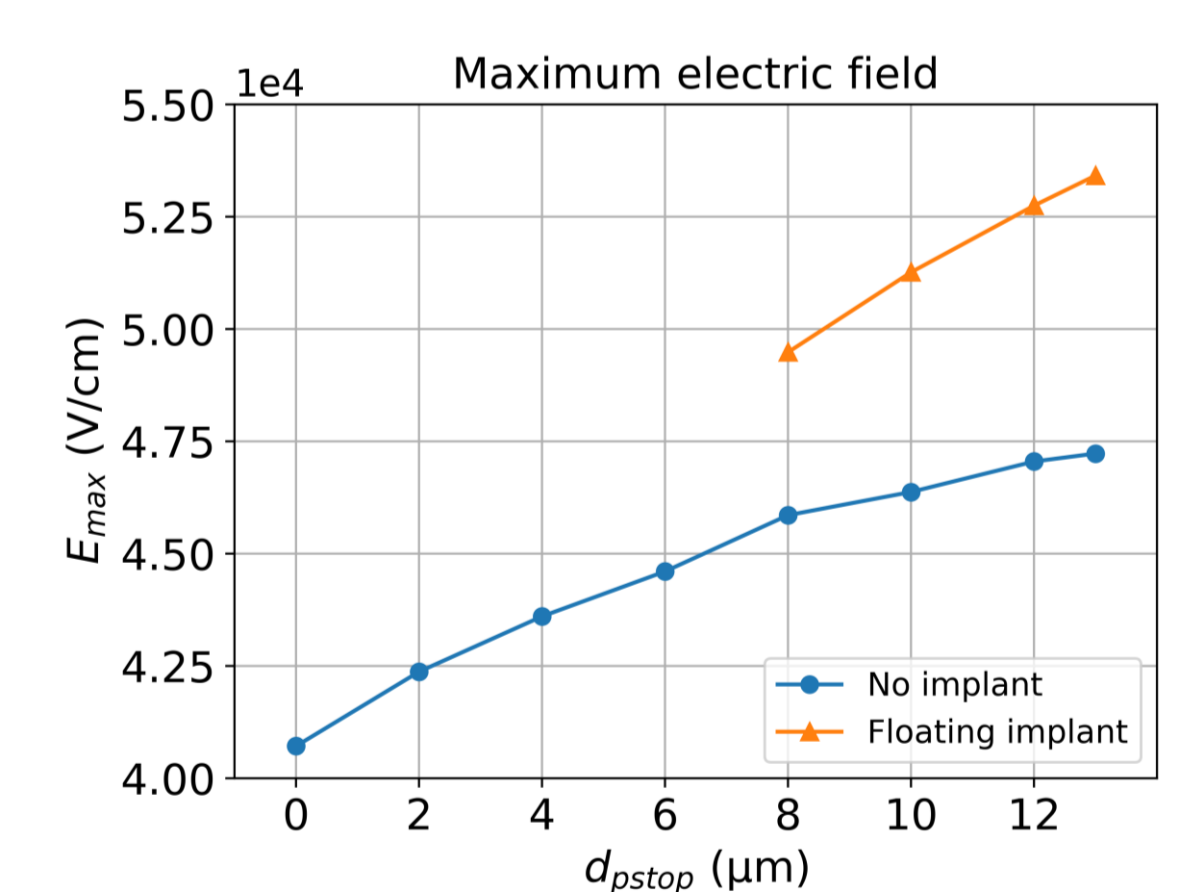
Efficiency analysis

- P-stop implant necessary to isolate single pixels in *n*-in-*p* sensors
- The closer the p-stops the higher the efficiency below the rail
- Common p-stop approach ($d = 0 \mu\text{m}$) shows highest efficiency between opposing pixels
- Additional implant below bias rail helps to set up uniform electric field between pixels (bias ring extension)
- Connected implant acts as additional strip which collects charge that is not available for further processing
- Design with floating implant reduces inefficiency below the rail
 - Similar performance as geometry without additional implantation



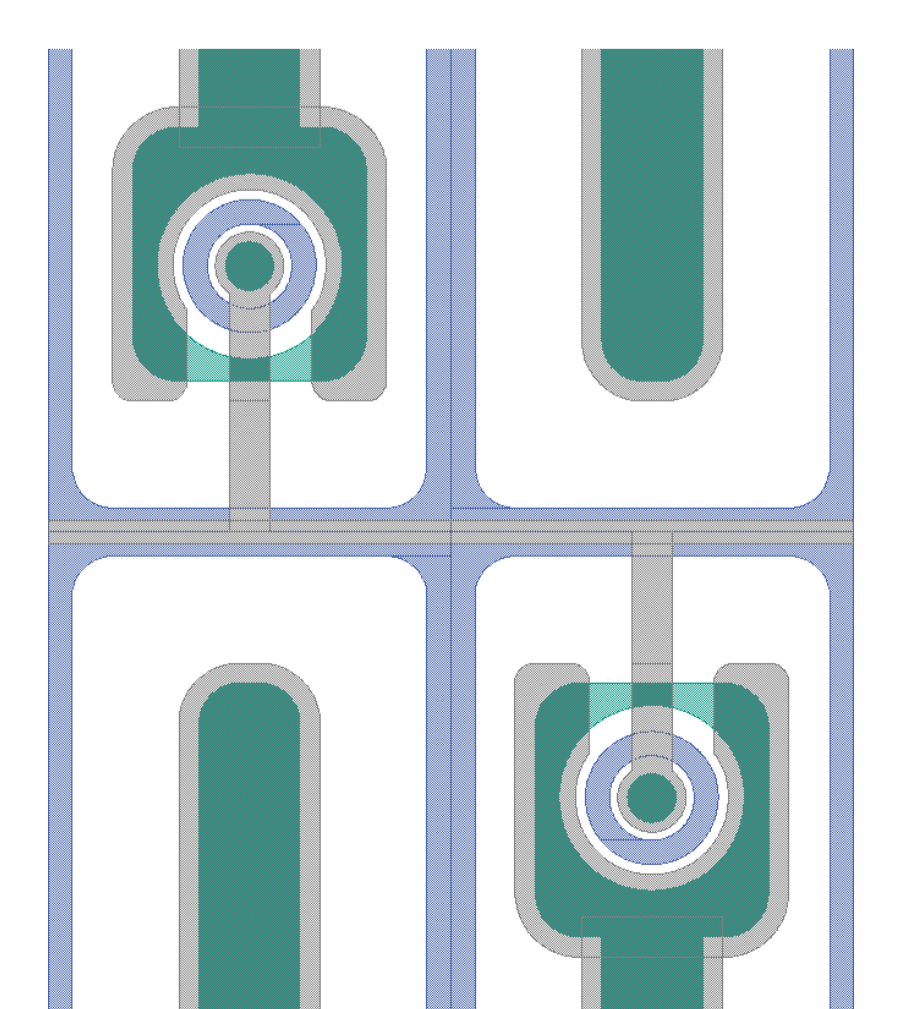
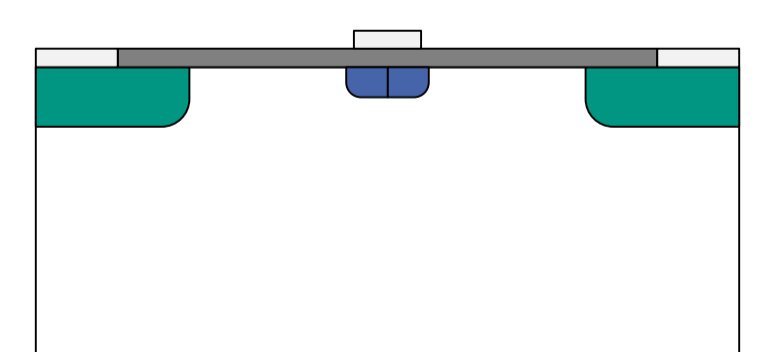
Maximum electric field in the bulk

- Sensor with floating implant shows an increased maximum electric field
- Maximum is always located at the interface between p-stop and silicon dioxide
- Closer p-stop rings lead to reduced field strength



Conclusion and outlook

- Bias rails with connected implant act as additional strips that collect almost all charge generated below them
- Common p-stop between opposing pixels preferable considering charge collection and maximum electric field
- Prototypes for further test beam studies expected in February 2018



Common p-stop prototype